

WIREBONDS STATUS

dE				E-front			E-back			Last checked			
strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd	date	detector
1				1	✓			1	/		/	9/21/07	dE, Ep, Eb
2				2				2	/		/		
3				3		~		3		/			
4				4				4					
5				5				5		/	/		
6				6				6		/			
7				7				7			/		
8				8				8					
9				9				9			/		
10				10				10		/			
11				11				11					
12				12				12	/				
13				13				13					
14				14				14	/	/			
15				15				15	/				
16				16				16					
17				17				17					
18				18				18	/				
19				19				19	/				
20				20				20	/				
21				21				21		/			
22				22				22	/				
23			X	23				23					
24				24				24					
25				25				25					
26				26				26	/				
27				27				27					
28				28				28	/				
29				29				29					
30				30				30					
31				31				31					
32				32				32					

Legend:

X = bond missing / = bond broken - = bond damaged

T22 4

AE = 2266-6
E = 2085-2

Defector Profile

BB7-1500

Wafer No.: **2085-2**

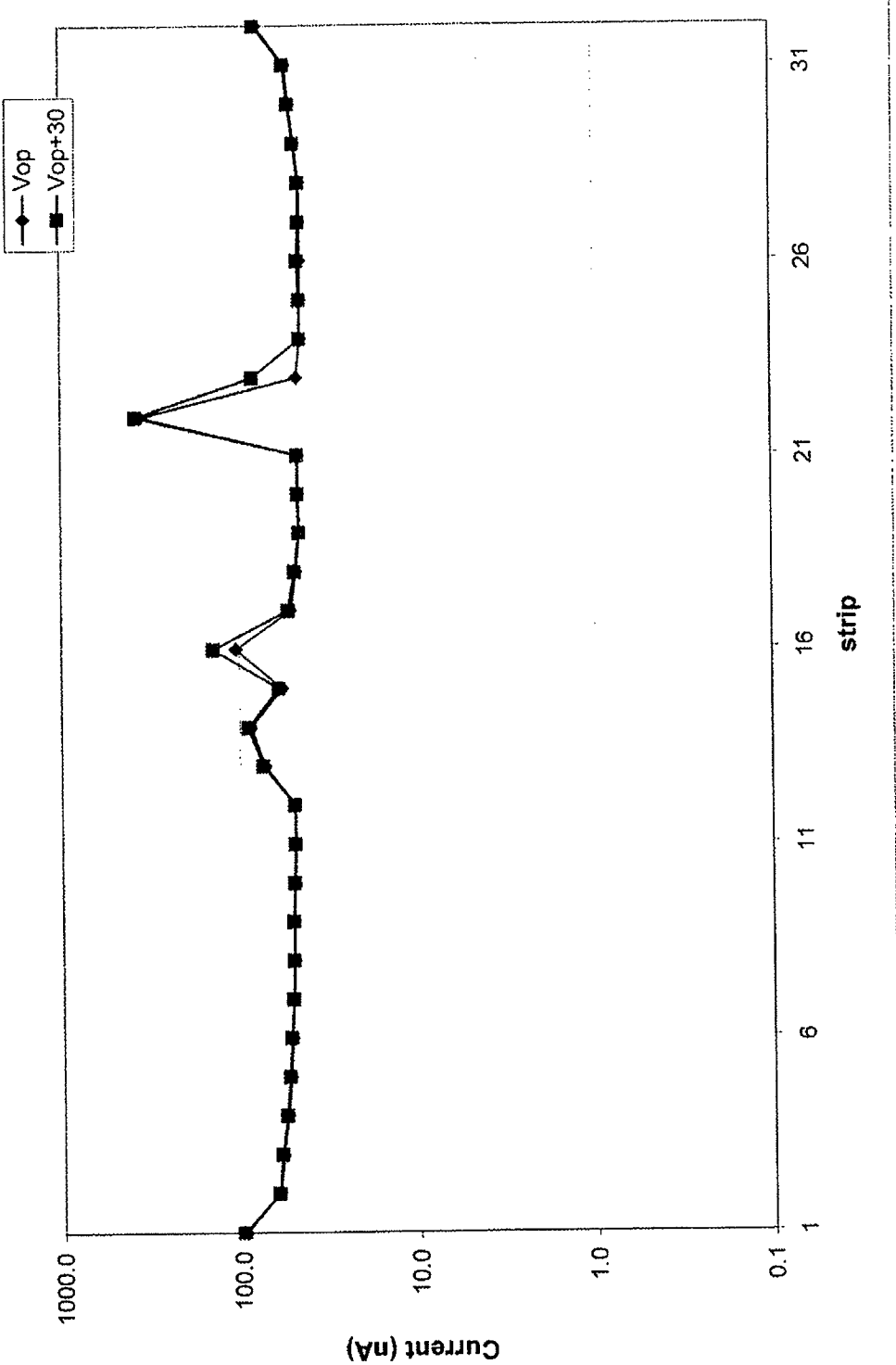
Thickness: **1489** μm

Depletion: **270** Volts

Front Side Data

Strip	Current (nA)	Vop	Vop+30
1	96.15	98.88	
2	62.09	62.35	
3	58.77	59.77	
4	55.16	56.09	
5	52.71	53.76	
6	51.72	52.36	
7	50.66	50.92	
8	49.82	50.15	
9	50.02	50.4	
10	49.15	49.49	
11	48.5	48.9	
12	48.7	49.06	
13	71.73	73.86	
14	86.02	89.03	
15	57.36	59.93	
16	104.74	141.02	
17	50.85	52.52	
18	47.58	48.46	
19	45.21	45.59	
20	45.85	46.17	
21	45.88	46.31	
22	355.7	378.7	
23	46.56	83.2	
24	44.23	44.57	
25	44.18	44.65	
26	44.14	45.85	
27	44.25	44.94	
28	44.41	45.03	
29	47.36	47.99	
30	50.43	51.27	
31	53.4	54.41	
32	77.42	79.76	
total	2080.8	2205.39	

Front Side Strip Leakage Current



HIGH LEAKAGE CURRENT RESULT DUE TO HIGHER ROOM TEMPERATURE AND HUMIDITY. (See Alpha resolution for current result in vacuum.)

ROOM TEMPERATURE = 25°C

HUMIDITY = 55%

Resolution Pro

HIRA BB7-1500

Wafer No.: 2085-2

Thickness: 1489 μm

JUNCTION

DET LINE: 63.8 KeV
SYSTEM: 41.6 KeV
CAL: 48.4 KeV

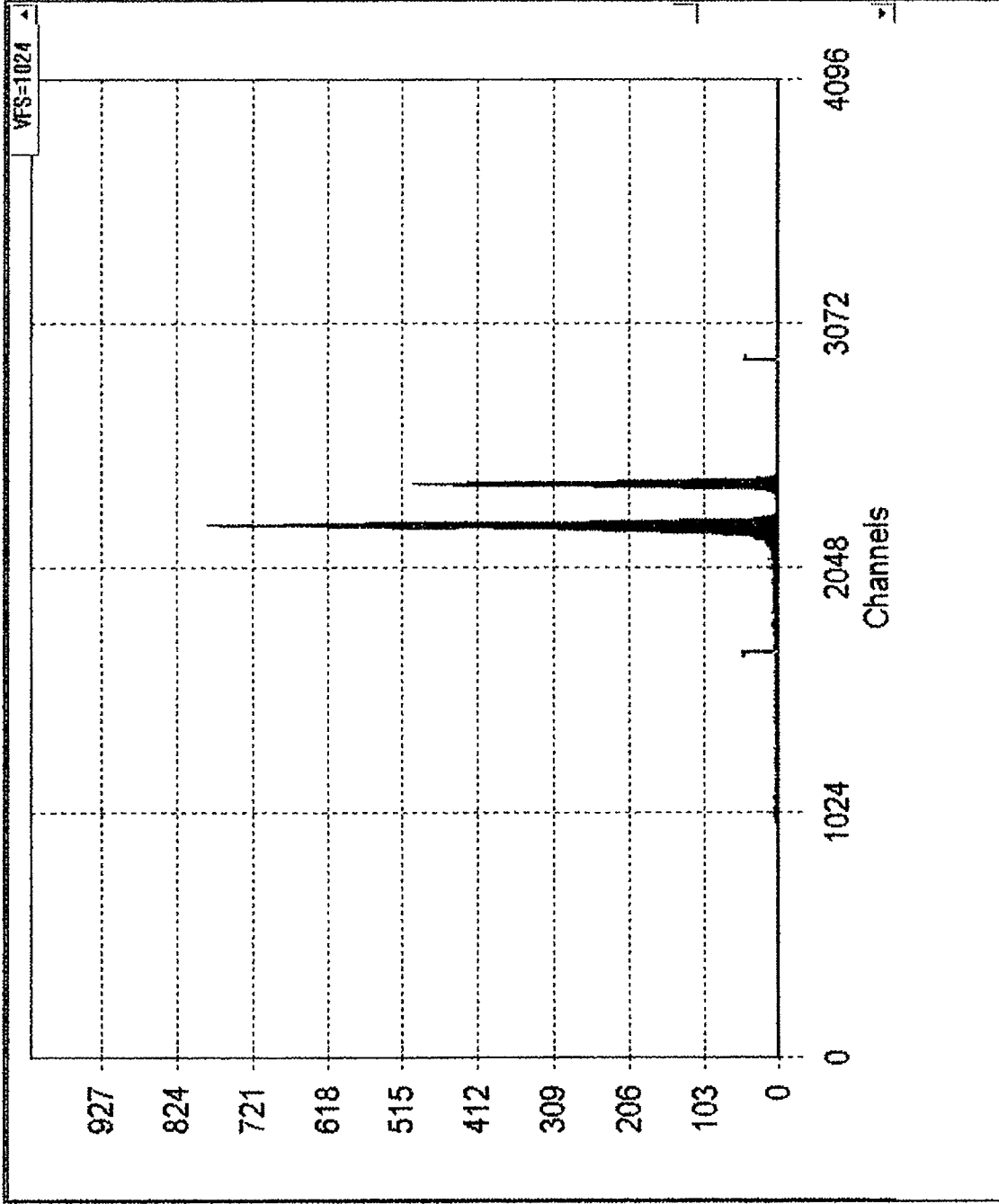
OHMIC

DET LINE: 66.4 KeV
SYSTEM: 41.1 KeV
CALC: 52.1 KeV

Source
Am 241

Rise Time
1

Flat Top
0



BIAS VOLTS= 300 V Leakage 1800 nA

INDIANA UNIVERSITY

BACK RESISTANCE MEASUREMENT:

DATE: 15/07/03
 DEVICE TYPE: HIRA BB7-D/S-1500
 DEVICE NUMBER: 2085-2
 THICKNESS: 1489 μ M
 OPERATING VOLTAGE: 270V

CHANNEL	OV	V.OP	V.OP + 30V
1-2	2.7K Ω	>1M Ω	>2M Ω
2-3	2.8K Ω	>1M Ω	>2M Ω
3-4	2.8K Ω	>1M Ω	>2M Ω
4-5	2.8K Ω	>1M Ω	>2M Ω
5-6	2.8K Ω	>1M Ω	>2M Ω
6-7	2.7K Ω	>1M Ω	>2M Ω
7-8	2.7K Ω	>1M Ω	>2M Ω
8-9	2.6K Ω	>1M Ω	>2M Ω
9-10	2.6K Ω	>1M Ω	>2M Ω
10-11	2.7K Ω	>1M Ω	>2M Ω
11-12	2.7K Ω	>1M Ω	>2M Ω
12-13	2.7K Ω	>1M Ω	>2M Ω
13-14	2.8K Ω	>1M Ω	>2M Ω
14-15	2.9K Ω	>1M Ω	>2M Ω
15-16	3.0K Ω	>1M Ω	>2M Ω
16-17	3.0K Ω	>1M Ω	>2M Ω
17-18	3.0K Ω	>1M Ω	>2M Ω
18-19	3.0K Ω	>1M Ω	>2M Ω
19-20	2.8K Ω	>1M Ω	>2M Ω
20-21	2.6K Ω	>1M Ω	>2M Ω
21-22	2.6K Ω	117K Ω	>1M Ω
22-23	2.6K Ω	114K Ω	>1M Ω
23-24	2.6K Ω	122K Ω	>1M Ω
24-25	2.6K Ω	156K Ω	>1M Ω
25-26	2.6K Ω	180K Ω	>1M Ω
26-27	2.7K Ω	175K Ω	>1M Ω
27-28	2.7K Ω	>1M Ω	>2M Ω
28-29	2.8K Ω	>1M Ω	>2M Ω
29-30	2.8K Ω	>1M Ω	>2M Ω
30-31	2.7K Ω	>1M Ω	>2M Ω
31-32	2.6K Ω	108K Ω	>1M Ω

Si-detector Inspection Record

Date: 9/21/2007 Time: 15:30
 Tel n.: 4
 Inspected detector(s): DE1, DE2, DE3
 1st inspector: W. HENZL
 2nd inspector: D. HENZL

WIREBONDS STATUS											
DE				E-front				E-back			
strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd
1				1	X			1	/	/	/
2				2			~	2	/	/	/
3				3				3	/	/	/
4				4				4			
5				5				5	/	/	/
6				6				6	/	/	/
7				7				7	/	/	/
8				8				8			
9				9				9	/	/	/
10				10				10	/	/	/
11				11				11			
12				12				12	/	/	/
13				13				13			
14				14				14	/	/	/
15				15				15	/	/	/
16				16				16			
17				17				17	/	/	/
18				18				18	/	/	/
19				19				19	/	/	/
20				20				20	/	/	/
21				21				21	/	/	/
22				22				22	/	/	/
23	X			23				23	/	/	/
24				24				24			
25				25				25			
26				26				26	/	/	/
27				27				27			
28				28				28	/	/	/
29				29				29			
30				30				30			
31				31				31			
32				32				32			

Legend: bonds crossed
 X = bond missing / = bond broken ~ = bond damaged

Overall detector status: (e.g. dusty surface, scratches, dirty frame and/or cable, status of telescope can ...)

Noise tests of detector n.: 20252 in telescope n.: 4

Date		electronics		CLASSIC		CHIF	
8-31-02		10-31-02					
E front		Chip 1 or shaper 3		Chip 0 or shaper 2		Chip 1 or shaper 1	
15	5	15	5	15	5	15	5
14	5	14	5	14	5	14	5
13	5	13	5	13	5	13	5
12	5	12	5	12	5	12	5
11	5	11	5	11	5	11	5
10	5	10	5	10	5	10	5
9	5	9	5	9	5	9	5
8	5	8	5	8	5	8	5
7	5	7	5	7	5	7	5
6	5	6	5	6	5	6	5
5	5	5	5	5	5	5	5
4	5	4	5	4	5	4	5
3	5	3	5	3	5	3	5
2	5	2	5	2	5	2	5
1	5	1	5	1	5	1	5
chn 0	~30mV	chn 0	~40mV	chn 0	~10mV	chn 0	~20mV
15	~110mV	15	~40mV	15	~35mV	15	~90mV
14	5	14	5	14	5	14	5
13	5	13	5	13	5	13	5
12	5	12	5	12	5	12	5
11	5	11	5	11	5	11	5
10	5	10	~130mV	10	5	10	5
9	5	9	5	9	5	9	5
8	5	8	5	8	5	8	5
7	5	7	5	7	5	7	5
6	5	6	5	6	5	6	5
5	5	5	5	5	5	5	5
4	5	4	~40mV	4	5	4	5
3	5	3	~40mV	3	5	3	5
2	5	2	5	2	5	2	5
1	5	1	5	1	5	1	5
chn 0	~20mV	chn 0	~40mV	chn 0	~30mV	chn 0	~90mV
15	~110mV	15	~40mV	15	~35mV	15	~90mV
14	5	14	5	14	5	14	5
13	5	13	5	13	5	13	5
12	5	12	5	12	5	12	5
11	5	11	5	11	5	11	5
10	5	10	5	10	5	10	5
9	5	9	5	9	5	9	5
8	5	8	5	8	5	8	5
7	5	7	5	7	5	7	5
6	5	6	5	6	5	6	5
5	5	5	5	5	5	5	5
4	5	4	5	4	5	4	5
3	5	3	5	3	5	3	5
2	5	2	5	2	5	2	5
1	5	1	5	1	5	1	5
chn 0	~20mV	chn 0	~40mV	chn 0	~30mV	chn 0	~90mV
15	~110mV	15	~40mV	15	~35mV	15	~90mV

off the
1st port
of 0513

Date: 12-8-07 Time: ~ 4:00 AM
 Inspected detector(s): DE + EF
 Detector number(s): 2266-6 (AE) + 2085-2 (E)
 What occasion: DE normal
 1st inspector: Vad Hantz
 2nd inspector: David Ferguson

WIREBONDS STATUS											
DE				E-front				E-back			
strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd
1				1	X			1			
2				2	N			2			
3				3				3			
4				4				4			
5				5				5			
6				6				6			
7				7				7			
8				8				8			
9		~		9				9			
10				10				10			
11		~		11				11			
12				12				12			
13				13				13			
14				14				14			
15				15				15			
16				16				16			
17				17				17			
18				18				18			
19				19				19			
20				20				20			
21				21				21			
22				22				22			
23				23	X			23			
24				24		~		24			
25				25				25			
26				26				26			
27				27				27			
28				28				28			
29				29		~		29			
30		~		30				30			
31				31				31			
32				32				32			

Legend: X = bond missing / = bond broken ~ = bond damaged
 bonds crossed

Overall detector status:
 (e.g. dusty surface, scratches, dirty frame and/or cable, status of telescope can ...)
 DE - wear @ strip 31
 EF - 22, 23, 25 strip dirty

Si-detector Inspection Record

Date: 10/8/2007 Time: 8:30am Tel n.: 4

Inspected detector(s): DE+FE

Detector number(s): 2266-6 +

What occasion: Part of DE

1st inspector: Vlad HENZL

2nd inspector: David HENZLOVA

WIREBONDS STATUS

DE			E-front			E-back					
strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd
1				1				1			
2				2				2			
3				3			~	3			
4				4				4			
5				5				5			
6				6				6			
7				7				7			
8				8				8			
9			~	9				9			
10		~		10				10			
11				11				11			
12				12				12			
13				13				13			
14				14				14			
15				15				15			
16				16				16			
17				17				17			
18				18				18			
19				19				19			
20				20				20			
21				21				21			
22			X	22				22			
23			~	23				23			
24				24				24			
25				25				25			
26				26				26			
27			~	27				27			
28			~	28				28			
29				29				29			
30				30				30			
31				31				31			
32				32				32			

Legend: = strip crossed / = bond broken ~ = bond damaged

Overall detector status:

(e.g. dusty surface, scratches, dirty frame and/or cable, status of telescope can ...)
 FE surface between strips
 FE - dirty frame of strips 23, 25
 DE surface foggy